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Irish Standard  
I.S. EN 61747-10-1:2013

# Liquid crystal display devices -- Part 10 -1: Environmental, endurance and mechanical test methods – Mechanical (IEC 61747-10-1:2013 (EQV))

## I.S. EN 61747-10-1:2013

*Incorporating amendments/corrigenda issued since publication:*

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**EN 61747-10-1**

October 2013

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Supersedes EN 61747-5:1998 (partially)

English version

**Liquid crystal display devices -  
Part 10-1: Environmental, endurance and mechanical test methods -  
Mechanical  
(IEC 61747-10-1:2013)**

Dispositifs d'affichage à cristaux liquides -  
Partie 10-1: Méthodes d'essais  
d'environnement, d'endurance et  
mécaniques -  
Essais mécaniques  
(CEI 61747-10-1:2013)

Flüssigkristall-Anzeige-Bauelemente -  
Teil 10-1: Umwelt-, Lebensdauer- und  
mechanische Prüfverfahren -  
Mechanisch  
(IEC 61747-10-1:2013)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Avenue Marnix 17, B - 1000 Brussels**

## Foreword

The text of document 110/395/CDV, future edition 1 of IEC 61747-10-1, prepared by IEC TC 110, "Electronic display devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61747-10-1:2013.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2014-05-14
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2016-08-14

This document partially supersedes EN 61747-5:1998.

EN 61747-10-1:2013 supersedes Clauses 1 and 2 of EN 61747-5:1998.

**NOTE** It is intended that the other clauses of EN 61747-5:1998 will be replaced by new parts in the EN 61747 series. The details of the intended changes are given in Annex D of EN 61747-30-1:2012.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

## Endorsement notice

The text of the International Standard IEC 61747-10-1:2013 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60068-1	NOTE Harmonised as EN 60068-1.
IEC 61747 series	NOTE Harmonised in EN 61747 series.
IEC 61747-5-3	NOTE Harmonised as EN 61747-5-3.

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068	Series	Environmental testing	EN 60068	Series
IEC 60068-2-6	-	Environmental testing - Part 2-6: Tests - Test Fc: Vibration (sinusoidal)	EN 60068-2-6	-
IEC 60068-2-7	-	Environmental testing - Part 2: Tests. Test Ga: Acceleration, steady state	EN 60068-2-7	-
IEC 60068-2-20	-	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	-
IEC 60068-2-21	-	Environmental testing - Part 2-21: Tests - Test U: Robustness of terminations and integral mounting devices	EN 60068-2-21	-
IEC 60068-2-27	-	Environmental testing - Part 2-27: Tests - Test Ea and guidance: Shock	EN 60068-2-27	-
IEC 60747	Series	Semiconductor devices	-	-
IEC 60748	Series	Semiconductor devices - Integrated circuits	-	-
IEC 60749-14	-	Semiconductor devices - Mechanical and climatic test methods - Part 14: Robustness of terminations (lead integrity)	EN 60749-14	-
IEC 61747-1	-	Liquid crystal and solid-state display devices - Part 1: Generic specification	EN 61747-1	-

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

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### **LIQUID CRYSTAL DISPLAY DEVICES –**

### **Part 10-1: Environmental, endurance and mechanical test methods – Mechanical**

#### **FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61747-10-1 has been prepared by IEC technical committee 110: Electronic display devices.

This first edition of IEC 61747-10-1 cancels and replaces Clauses 1 and 2 of the first edition of IEC 61747-5 published in 1998. This edition constitutes a technical revision.

**NOTE** It is intended that the other clauses of IEC 61747-5:1998 will be replaced by new parts in the IEC 61747 series. The details of the intended changes are given in Annex D of IEC 61747-30-1:2012.



The text of this standard is based on the following documents:

CDV	Report on voting
110/395/CDV	110/454/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61747 series, published under the general title *Liquid crystal display devices* can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

## LIQUID CRYSTAL DISPLAY DEVICES –

### Part 10-1: Environmental, endurance and mechanical test methods – Mechanical

#### 1 Scope

This part of IEC 61747 lists test methods applicable to liquid crystal display devices. It takes into account, wherever possible, the mechanical robustness test methods as outlined in IEC 60068.

NOTE Devices include cells and modules.

The object of this standard is to establish uniform preferred test methods with preferred values for stress levels for judging the mechanical properties of liquid crystal display devices.

In case of contradiction between this standard and a relevant specification, it is the latter that should govern.

#### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068 (all parts), *Environmental testing*

IEC 60068-2-6, *Environmental testing – Part 2-6: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-7, *Basic environmental testing procedures – Part 2-7: Tests – Test Ga and guidance: Acceleration, steady state*

IEC 60068-2-20, *Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads*

IEC 60068-2-21, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27, *Environmental testing – Part 2-27: Tests – Test Ea and guidance: Shock*

IEC 60747 (all parts), *Semiconductor devices*

IEC 60748 (all parts), *Semiconductor devices – Integrated circuits*

IEC 60749-14, *Semiconductor devices – Mechanical and climatic test methods – Part 14: Robustness of terminations (lead integrity)*

IEC 61747-1, *Liquid crystal and solid-state display devices – Part 1: Generic specification*

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